SCLS070A - NOVEMBER 1988 - REVISED NOVEMBER 1990

- **High-Current 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers**
- Inputs Are TTL-Voltage Compatible
- **Package Options Include Plastic** Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

These bus buffers feature independent line drivers with 3-state outputs. Each output is disabled when the associated OE is low.

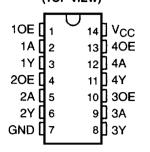
The SN54HCT126 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HCT126 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

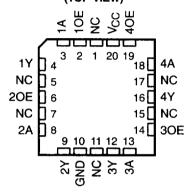
INF	PUTS	OUTPUT
OE	Α	Y
Н	Н	Н
Н	L	L
L	X	z

H = high level, L = low level, X = irrelevant

SN54HCT126...J PACKAGE SN74HCT126...D OR N PACKAGE (TOP VIEW)



SN54HCT126...FK PACKAGE (TOP VIEW)



NC - No internal connection

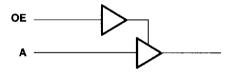
logic symbol[†]

	1				1	
10E	2	EN	\triangleright	▽	3	1 Y
1A 2OE	4	\vdash			6	
20L 2A	5	ŀ				2Y
30E	10				8	
3A	9	ŀ				3Y
40E	13				11	
4A	12					4Y
					l	

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

logic diagram, each buffer (positive logic)



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SN54HCT126, SN74HCT126 QUADRUPLE BUS BUFFER GATES WITH 3-STATE OUTPUTS

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absolute maximum ratings over operating free-air temperature ranget

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±35 mA
Continuous current through V _{CC} or GND pins	±70 mA
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package	
Lead temperature 1,6 mm (1/16 in) from case for 10 s: DW or N package	260°C
Storage temperature range	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		·	SN54HCT126		SN74HCT126			LINUT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	્રે 5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	V _{CC} = 4.5 V to 5.5 V	2	(2			٧
ViL	Low-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0		0.8	0		0.8	٧
٧ _I	Input voltage		0	- A.	VCC	0		VCC	٧
Vο	Output voltage		0		VCC	0		VCC	٧
tţ	Input transition (rise and fall) time		0	3	500	0		500	ns
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		T _A = 25°C			SN54HCT126		SN74HCT126		LINUT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Vari	V _I = V _{IH} or V _{IL} , I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		v
VOH	VI = VIH or VIL, IOH = -6 mA	7 4.5 V	3.98	4.3		3.7		3.84		V
	VI = VIH or VIL, IOL = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
VOL	VI = VIH or VIL, IOL = 6 mA	7 4.5 V		0.17	0.26		0.4		0.33	V
11	V _I = V _{CC} or 0	5.5 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0, $V_I = V_{IH}$ or V_{IL}	5.5 V		±0.01	±0.5	J.A.	±10		±5	μΑ
^I cc	$V_I = V_{CC}$ or 0, $I_O = 0$	5.5 V			8		160		80	μΑ
∆l _{CC} ‡	One input at 0.5 V or 2.4 V, Other inputs at 0 or V _{CC}	5.5 V		1.4	2.4		3		2.9	mA
C _i		4.5 V to 5.5 V		3	10		10*		10	рF

^{*} On products compliant to MIL-STD-883C, Class B, this parameter is not production tested.



[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	V	T,	λ = 25°C	;	SN54H	CT126	SN74H	CT126	LIBRET	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
	A	Y	4.5 V		15	26		39		33		
^t pd	^	1	5.5 V		12	23		35		30	ns	
•	0.5	Y	4.5 V		19	26		39		33	20	
^t en	OE		5.5 V		15	23		35		30	ns	
.	OE		Y	4.5 V		18	26	6	39		33	
^t dis		Ţ	5.5 V		15	23	250	35		30	ns	
t _t		Anu	4.5 V		8	15		22		19	no	
		Any 5.5 V	5.5 V		7	14	***	21		17	ns	

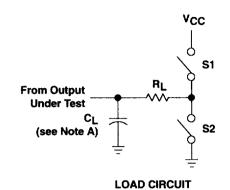
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	V	T,	λ = 25°C	;	SN54H	CT126	SN74H	CT126	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
		V	4.5 V		21	36		58		46	
^t pd	A	,	5.5 V		17	32		48		42	ns
	OE	Y	4.5 V		25	36	A.	58		46	***
^t en			5.5 V		21	32		48		42	ns
4.	4	A	4.5 V		17	42		63		53	
i it		Any	5.5 V		14	38	- 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1	57		48	ns

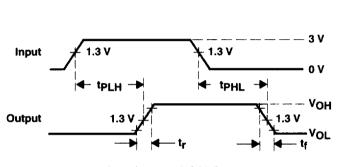
operating characteristics, $T_A = 25^{\circ}C$

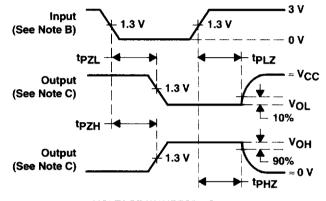
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} F	Power dissipation capacitance	No load	35	pF

PARAMETER MEASUREMENT INFORMATION



PARAI	PARAMETER		RL CL		S2
	tpzH	1 kΩ	50 pF or	Open	Closed
^t en	tPZL	1 K32	150 pF	Closed	Open
•	t _{PHZ}	1 kΩ	50 pF	Open	Closed
^t dis	tPLZ	1 1,52	50 pr	Closed	Open
t _{pd} or t _t		-	50 pF or 150 pF	Open	Open





VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES

VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES

NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_{O} = 50 \Omega$, $t_{f} \leq$ 6 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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